

The effect of contamination on the S1 triplet component in DarkSide-50 dark matter experiment



Clea Sunny

AstroCeNT, CAMK PAN, Warsaw on behalf of the DarkSide-50 Collaboration VIEnna Workshop on Simulations 2024 (VIEWS24) 26th April 2024 - Vienna, Austria

Direct detection of WIMPs in DarkSide-50

- Located at Gran Sasso National Laboratory (LNGS), Italy.
- Dual-phase TPC: 46.4 ± 0.6 kg of active Underground Argon (UAr)
- S1 Primary scintillation signal in LAr.
- S2 Secondary scintillation (electroluminescence) signal in GAr layer.
- Precise determination of event positions in all 3-dimensions in TPC.
- DM-induced Nuclear Recoils (NR).
- Background-induced Electron Recoils (ER).
- Excellent signal to background discrimination power based on NR and ER pulse shapes.

378 f90 ~ 0.3 376 **Electron Recoil (ER)** 374 Credits: M. Wada's talk 372 at La Thuile 370 368 -2 10 Clea Sunny, 26th April 2024 sample time [us]



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Credits: M. Wada's talk LIDINE 2022

DS-50 - Purpose of analysis 0.4 1.0 1.5 0.08 Data day) kg Low energy background analysis in DS-50 encountered an 0.0 Ne ß excess number of events at 1-4 Ne, when the inline getter (0.2 0.0 was bypassed (120 hours). Events 0.005 The Spurious Electron (SE) event rate reduced after the getter re-installation.

- This may imply that the cause of SEs could be an Ο impurity that exist in the gas phase.
- Given that N₂ is highly volatile at 87 K, it is Ο considered as one of the prime suspects.
- N, hypothesis testing Triplet analysis. Ο

Credits: P. Agnes et al. Phys. Rev. D 107, 063001

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Effect of N₂ contamination on the S1 signal - Test study by WArP collaboration

- Contaminants in LAr, such as N₂, O₂, H₂O, CO, etc., quench Ar scintillation photons.
- Effect of N₂ contamination in LAr has already been studied (WArP).
- Quenching of light yield in N₂- contaminated LAr is expected.
- $Ar_2^* + N_2 \implies 2Ar + N_2$
- The Ar excimers in the **triplet state** are more affected by N₂.
- Thus, analyzing S1 triplet component may help understand the presence of impurities in LAr, **especially N**₂.



Triplet lifetime event-by-event analysis -Data selection

- UAr data of DS-50 acquired between April 2015 and April 2018.
- Event-by-event analysis.

The selection cuts used are as follows:

- 1. S2 > 0 : For selecting events with both S1 and S2 signals.
- 2. $0.1 < S1_{90} < 0.5$: The fprompt for selecting ER events.
- 3. $\Delta t > 20 \times 10^{-3} s$: To avoid S1 pile-ups.
- 4. t_{drift} > 20 µs : To avoid overlapping between S1 and S2 signals.
- 1000 < S1 < 1600 PE: Lower limit for minimum statistics and upper limit to avoid saturation.
- 6. $S1_{fwhm} < 0.1 \ \mu s$: To avoid pile up in S1 and S2.
- 7. $S1_{|tba|} < 0.9$: To obtain better events from the center of the fiducial volume.





The waveform model

Refer: P. Agnes et al 2021 JINST 16 P11026

- To model the waveform, a function which is a convolution of three contributions is considered:
 - Ar scintillation time profile;

$$F(t,\tau_{s},\tau_{t},p_{s}) = \frac{p_{s}}{\tau_{s}}e^{-t/\tau_{s}} + \frac{1-p_{s}}{\tau_{t}}e^{-t/\tau_{t}}$$

where $\tau_s(\tau_t)$ is the singlet (triplet) decay times, and $p_s(1 - p_s)$ the populating probability of singlet (triplet) state.

• TPB re-emission contribution;

$$H(t, \tau_{TPB}, p_{TPB}) = (1 - p_{TPB}) + \frac{p_{TPB}}{\tau_{TPB}} e^{\frac{1}{\tau_{TPB}}}$$

Here, $p_0 = 1 - p_{TPB}$ is the amplitude of prompt TPB re-emission component. p_{TPB} and τ_{TPB} are the amplitude and lifetime of delayed TPB component, respectively.

TPB (TetraPhenyl Butadiene) is a wavelength shifter used in DS-50. TPB has one prompt and more than one delayed re-emission components. In this analysis, only one delayed component is considered for TPB.

• Detector response, which is described with a gaussian distribution with a peak at t_0 which is the reference time, and the resolution σ ;

$$G(t, \sigma) = \frac{e^{-t^2/2\sigma}}{\sqrt{2\pi\sigma^2}}$$

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The waveform model

• The **total (overall response) function**, which is the convolution of the three contributions, associated with the pulse amplitude (*A*);

$$P(t, \theta, t_0, A) = A \times R(t', \theta)$$

where

$$\begin{split} R(t, \theta) &= F\Big(t, \tau_s, \tau_t, p_s\Big) \circledast H\Big(t, \tau_{TPB}, p_{TPB}\Big) \circledast G(t, \sigma) \\ t' &= t - t_o, \end{split}$$

 θ is the set of parameters including;

- p_s , p_t , the probabilities to populate singlet and triplet states, respectively, and
- $\tau_{\rm s}$ and $\tau_{\rm t}$, decay times of singlet and triplet states, respectively.



Triplet analysis on the average waveform - A Previous study

- Similar analysis already done by fitting on the average waveform (wf).
- Selection cut: **S1 in [100, 20000] PE**.
 - \circ Selected wfs are grouped into sets of 5.10⁴.
 - Performed fit on each average wf using the total function in the range [0.01, 10] μs.
- Triplet lifetime observed by the average waveform approach is 1.375 ± 0.001 μs.
- No reduction in triplet lifetime during getter-off is observed.



Parameters	Before	During	After
$ au_l$	$1.375\pm0.005\;\mu\mathrm{s}$	$1.375\pm0.008~\mu\mathrm{s}$	$1.375 \pm 0.001 \; \mu { m s}$
p_l	0.694 ± 0.003	0.695 ± 0.005	0.6958 ± 0.0006
$ au_s$	$0.01368 \pm 0.00008 \ \mu {\rm s}$	$0.0136\pm0.0001\;\mu{\rm s}$	$0.01367 \pm 0.00002 \ \mu {\rm s}$
p_s	0.306 ± 0.003	0.305 ± 0.005	0.3042 ± 0.0006
$ au_{TPB}$	$213\pm5~\mathrm{ns}$	$212\pm9~\mathrm{ns}$	$209\pm1~\mathrm{ns}$
p_{TPB}	0.285 ± 0.006	0.29 ± 0.01	0.282 ± 0.001

Triplet lifetime event-by-event analysis - Method of analysis

- Collected 1000 events/run from the whole 3-year dataset, except for getter-off runs.
- **Re-binned**: All bins in the fit ranges have at least 10 PE.
- The error on each wf is the statistical error.
- Modelling the wf;
 - Total fn. for the multi-components
 - Exponential fn. for the single-component.
- Chi-square fitting on each individual wf;
 - Total fn. is fitted over the range **[0.018, 4.75] μs.**
 - Exponential fn. is fitted over the range **[0.15, 4.75] μs.**
- Grouped them into bins of days.



Results from event-wise analysis - Triplet lifetime in DS-50 over 3 years



- Overall increase of $\tau_{\rm trin}$ by ~ 0.43%.
 - May correspond to the purity increase in LAr after getter re-installation.
- No degradation of *τ*_{trip} during getter-off period is observed;
 - N₂ concentration in DS-50 LAr < 1 ppm
 - \sim N, may not be the cause of SEs.
- Event-by-event approach, τ_{trip} 1.4070 ± 0.00006 µs Average wf approach, τ_{trip} - 1.375 ± 0.001 µs
- Triplet lifetime value from event-wise analysis is not consistent with that from the average wf analysis.
 - The difference could be from the **uncertainties in the fit models.**
 - Systematic uncertainty under evaluation.

Scope of simulations in the analysis

- The few-extracted electrons and their corresponding N_{e-} distributions are modelled with G4DS.
- One and two *e* peak well described by Gaussians, and are in good agreement with getter-off data.
- Without understanding the cause of SE, simulating their behavior for predicting occurrences of SE events in future experiments is not feasible.



Credits: Phys. Rev. Lett. 121, 081307

Summary

- The purpose of this S1 triplet component analysis is to test the hypothesis of N₂ causing the SEs.
- This is an event-by-event analysis.
- The decay time of triplet component from our analysis is found to be **1.4070 ± 0.00006 μs**.
- A visible reduction in the triplet lifetime was expected at ~ 1 ppm of N_2 concentration.
- No reduction in the triplet lifetime is observed during the getter-off period;
 - If the LAr in DS-50 is N₂-contaminated, then the concentration of N₂ in the LAr is less than 1 ppm.
 - This may also imply that **N**, may not be the cause of SEs.
- An **overall increase in the triplet lifetime is observed** over the whole dataset of 3 years after the getter is re-installed;
 - The observed wf change is consistent with the increase in the lifetime of triplet component.
 - This increase **may** correspond to the increase in the purity of the LAr after re-installing getter.



Backup slides

Counts per day-bin



- Grouped each fitted wf in 25-day bins and a 3-day bin from the start till getter-off period.
- Getter-off waveforms are grouped in a 4-day bin from run 12922-12977. Skipped first day to get pure getter-off data
- Rest of the waveforms after getter re-installation are again grouped into 25 days bins.

Statistics in a bin





Exclusion plot



Figure: Spin-independent WIMP- nucleon cross section 90 % C.L. exclusion plots for the DarkSide-50 AAr (dotted red) and UAr campaigns (dashed red), and combination of the UAr and AAr [1] campaigns (solid red).